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**Understanding Embedded - CPLDs (Complex Programmable Logic Devices)** 

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### **Applications of Embedded - CPLDs**

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	2
Number of Macrocells	32
Number of Gates	600
Number of I/O	36
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LCC (J-Lead)
Supplier Device Package	44-PLCC (16.59x16.59)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7032slc44-10f

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, and VeriBest
- Programming support
  - Altera's Master Programming Unit (MPU) and programming hardware from third-party manufacturers program all MAX 7000 devices
  - The BitBlaster<sup>TM</sup> serial download cable, ByteBlasterMV<sup>TM</sup> parallel port download cable, and MasterBlaster<sup>TM</sup> serial/universal serial bus (USB) download cable program MAX 7000S devices

# General Description

The MAX 7000 family of high-density, high-performance PLDs is based on Altera's second-generation MAX architecture. Fabricated with advanced CMOS technology, the EEPROM-based MAX 7000 family provides 600 to 5,000 usable gates, ISP, pin-to-pin delays as fast as 5 ns, and counter speeds of up to 175.4 MHz. MAX 7000S devices in the -5, -6, -7, and -10 speed grades as well as MAX 7000 and MAX 7000E devices in -5, -6, -7, -10P, and -12P speed grades comply with the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2.* See Table 3 for available speed grades.

Device	Speed Grade									
	-5	-6	-7	-10P	-10	-12P	-12	-15	-15T	-20
EPM7032		<b>✓</b>	<b>✓</b>		<b>✓</b>		<b>✓</b>	<b>✓</b>	<b>✓</b>	
EPM7032S	<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>					
EPM7064		<b>✓</b>	<b>✓</b>		~		<b>✓</b>	<b>✓</b>		
EPM7064S	<b>✓</b>	<b>✓</b>	<b>✓</b>		~					
EPM7096			<b>✓</b>		~		<b>✓</b>	<b>✓</b>		
EPM7128E			<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7128S		<b>✓</b>	<b>✓</b>		~			<b>✓</b>		
EPM7160E				<b>✓</b>	<b>✓</b>		<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7160S		<b>✓</b>	<b>✓</b>		~			<b>✓</b>		
EPM7192E						<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7192S			<b>✓</b>		<b>✓</b>			<b>✓</b>		
EPM7256E						<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7256S			<b>✓</b>		<b>✓</b>			<b>✓</b>		

The MAX 7000E devices—including the EPM7128E, EPM7160E, EPM7192E, and EPM7256E devices—have several enhanced features: additional global clocking, additional output enable controls, enhanced interconnect resources, fast input registers, and a programmable slew rate.

In-system programmable MAX 7000 devices—called MAX 7000S devices—include the EPM7032S, EPM7064S, EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices. MAX 7000S devices have the enhanced features of MAX 7000E devices as well as JTAG BST circuitry in devices with 128 or more macrocells, ISP, and an open-drain output option. See Table 4.

Table 4. MAX 7000 Device Feat	ures		
Feature	EPM7032 EPM7064 EPM7096	All MAX 7000E Devices	All MAX 7000S Devices
ISP via JTAG interface			✓
JTAG BST circuitry			<b>√</b> (1)
Open-drain output option			<b>✓</b>
Fast input registers		<b>✓</b>	✓
Six global output enables		<b>✓</b>	✓
Two global clocks		✓	✓
Slew-rate control		<b>✓</b>	✓
MultiVolt interface (2)	✓	<b>✓</b>	<b>✓</b>
Programmable register	✓	<b>✓</b>	✓
Parallel expanders	<b>✓</b>	✓	✓
Shared expanders	<b>✓</b>	<b>✓</b>	<b>✓</b>
Power-saving mode	✓	✓	✓
Security bit	✓	✓	✓
PCI-compliant devices available	✓	✓	✓

#### Notes:

- (1) Available only in EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices only.
- (2) The MultiVolt I/O interface is not available in 44-pin packages.

MAX 7000 devices contain from 32 to 256 macrocells that are combined into groups of 16 macrocells, called logic array blocks (LABs). Each macrocell has a programmable-AND/fixed-OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with both shareable expander product terms and high-speed parallel expander product terms to provide up to 32 product terms per macrocell.

The MAX 7000 family provides programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 7000E and MAX 7000S devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000 devices (except 44-pin devices) can be set for either 3.3-V or 5.0-V operation, allowing MAX 7000 devices to be used in mixed-voltage systems.

The MAX 7000 family is supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.



For more information on development tools, see the MAX+PLUS II Programmable Logic Development System & Software Data Sheet and the Quartus Programmable Logic Development System & Software Data Sheet.

# Functional Description

The MAX 7000 architecture includes the following elements:

- Logic array blocks
- Macrocells
- Expander product terms (shareable and parallel)
- Programmable interconnect array
- I/O control blocks

The MAX 7000 architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. Figure 1 shows the architecture of EPM7032, EPM7064, and EPM7096 devices.

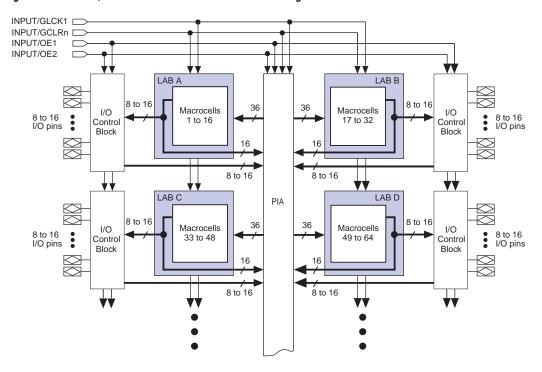


Figure 1. EPM7032, EPM7064 & EPM7096 Device Block Diagram

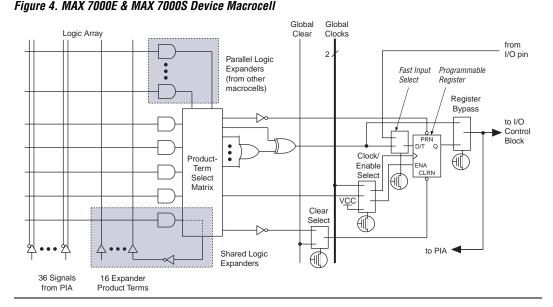


Figure 4 shows a MAX 7000E and MAX 7000S device macrocell.

Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register clear, preset, clock, and clock enable control functions. Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product-term allocation according to the logic requirements of the design.

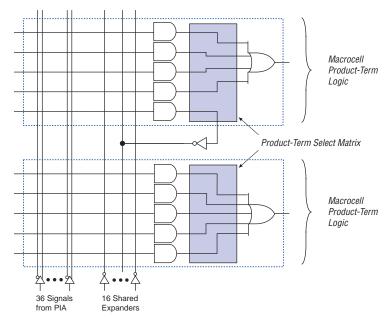
For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera development software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

## Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 5 shows how shareable expanders can feed multiple macrocells.

Figure 5. Shareable Expanders

Shareable expanders can be shared by any or all macrocells in an LAB.



### Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to  $V_{CC}$ , the output is enabled.

The MAX 7000 architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

## In-System Programmability (ISP)

MAX 7000S devices are in-system programmable via an industry-standard 4-pin Joint Test Action Group (JTAG) interface (IEEE Std. 1149.1-1990). ISP allows quick, efficient iterations during design development and debugging cycles. The MAX 7000S architecture internally generates the high programming voltage required to program EEPROM cells, allowing in-system programming with only a single 5.0 V power supply. During in-system programming, the I/O pins are tri-stated and pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k%.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board with standard in-circuit test equipment before they are programmed. MAX 7000S devices can be programmed by downloading the information via in-circuit testers (ICT), embedded processors, or the Altera MasterBlaster, ByteBlasterMV, ByteBlaster, BitBlaster download cables. (The ByteBlaster cable is obsolete and is replaced by the ByteBlasterMV cable, which can program and configure 2.5-V, 3.3-V, and 5.0-V devices.) Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling and allows devices to be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. Because some in-circuit testers cannot support an adaptive algorithm, Altera offers devices tested with a constant algorithm. Devices tested to the constant algorithm have an "F" suffix in the ordering code.

The Jam<sup>TM</sup> Standard Test and Programming Language (STAPL) can be used to program MAX 7000S devices with in-circuit testers, PCs, or embedded processor.



For more information on using the Jam language, refer to AN 122: Using Jam STAPL for ISP & ICR via an Embedded Processor.

The ISP circuitry in MAX 7000S devices is compatible with IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

## **Programming Sequence**

During in-system programming, instructions, addresses, and data are shifted into the MAX 7000S device through the TDI input pin. Data is shifted out through the TDO output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

- Enter ISP. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.
- 2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.
- 3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.
- Program. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.
- Verify. Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.
- 6. Exit ISP. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

The programming times described in Tables 6 through 8 are associated with the worst-case method using the enhanced ISP algorithm.

Table 6. MAX 7000S t <sub>PU</sub>	able 6. MAX 7000S t <sub>PULSE</sub> & Cycle <sub>TCK</sub> Values									
Device	Progra	ımming	Stand-Alone	Verification						
	t <sub>PPULSE</sub> (s)	Cycle <sub>PTCK</sub>	t <sub>VPULSE</sub> (s)	Cycle <sub>VTCK</sub>						
EPM7032S	4.02	342,000	0.03	200,000						
EPM7064S	4.50	504,000	0.03	308,000						
EPM7128S	5.11	832,000	0.03	528,000						
EPM7160S	5.35	1,001,000	0.03	640,000						
EPM7192S	5.71	1,192,000	0.03	764,000						
EPM7256S	6.43	1,603,000	0.03	1,024,000						

Tables 7 and 8 show the in-system programming and stand alone verification times for several common test clock frequencies.

Table 7. MAX 7000S In-System Programming Times for Different Test Clock Frequencies										
Device				f	TCK				Units	
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz		
EPM7032S	4.06	4.09	4.19	4.36	4.71	5.73	7.44	10.86	s	
EPM7064S	4.55	4.60	4.76	5.01	5.51	7.02	9.54	14.58	S	
EPM7128S	5.19	5.27	5.52	5.94	6.77	9.27	13.43	21.75	S	
EPM7160S	5.45	5.55	5.85	6.35	7.35	10.35	15.36	25.37	S	
EPM7192S	5.83	5.95	6.30	6.90	8.09	11.67	17.63	29.55	S	
EPM7256S	6.59	6.75	7.23	8.03	9.64	14.45	22.46	38.49	S	

Table 8. MAX 7000S Stand-Alone Verification Times for Different Test Clock Frequencies										
Device				1	тск				Units	
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz		
EPM7032S	0.05	0.07	0.13	0.23	0.43	1.03	2.03	4.03	s	
EPM7064S	0.06	0.09	0.18	0.34	0.64	1.57	3.11	6.19	S	
EPM7128S	0.08	0.14	0.29	0.56	1.09	2.67	5.31	10.59	S	
EPM7160S	0.09	0.16	0.35	0.67	1.31	3.23	6.43	12.83	S	
EPM7192S	0.11	0.18	0.41	0.79	1.56	3.85	7.67	15.31	S	
EPM7256S	0.13	0.24	0.54	1.06	2.08	5.15	10.27	20.51	S	

## Operating Conditions

Tables 13 through 18 provide information about absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V MAX 7000 devices.

Table 1	3. MAX 7000 5.0-V Device Abso	plute Maximum Ratings Note (1)			
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-2.0	7.0	V
VI	DC input voltage		-2.0	7.0	V
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA
T <sub>STG</sub>	Storage temperature	No bias	-65	150	° C
T <sub>AMB</sub>	Ambient temperature	Under bias	-65	135	° C
TJ	Junction temperature	Ceramic packages, under bias		150	°C
		PQFP and RQFP packages, under bias		135	°C

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CCINT</sub>	Supply voltage for internal logic and input buffers	(3), (4), (5)	4.75 (4.50)	5.25 (5.50)	V
V <sub>CCIO</sub>	Supply voltage for output drivers, 5.0-V operation	(3), (4)	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output drivers, 3.3-V operation	(3), (4), (6)	3.00 (3.00)	3.60 (3.60)	V
V <sub>CCISP</sub>	Supply voltage during ISP	(7)	4.75	5.25	V
V <sub>I</sub>	Input voltage		-0.5 (8)	V <sub>CCINT</sub> + 0.5	V
Vo	Output voltage		0	V <sub>CCIO</sub>	V
T <sub>A</sub>	Ambient temperature	For commercial use	0	70	°C
		For industrial use	-40	85	°C
TJ	Junction temperature	For commercial use	0	90	°C
		For industrial use	-40	105	° C
t <sub>R</sub>	Input rise time			40	ns
t <sub>F</sub>	Input fall time			40	ns

Table 2	21. MAX 7000 & MAX 7000E Ext	ernal Timing Param	eters Note	(1)			
Symbol	Parameter	Conditions		Speed (	Grade		Unit
			MAX 700	0E (-10P)	MAX 70		
			Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t <sub>SU</sub>	Global clock setup time		7.0		8.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.5		0.5		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		5.0		5	ns
t <sub>CH</sub>	Global clock high time		4.0		4.0		ns
t <sub>CL</sub>	Global clock low time		4.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		2.0		3.0		ns
t <sub>AH</sub>	Array clock hold time		3.0		3.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		10.0		10.0	ns
t <sub>ACH</sub>	Array clock high time		4.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		4.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	4.0		4.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			10.0		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	100.0		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			10.0		10.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	100.0		100.0		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	125.0		125.0		MHz

Symbol	Parameter	Conditions		Speed	Grade		Unit
			MAX 700	OE (-10P)		00 (-10) DOE (-10)	
			Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.5		1.0	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.5		1.0	ns
t <sub>FIN</sub>	Fast input delay	(2)		1.0		1.0	ns
t <sub>SEXP</sub>	Shared expander delay			5.0		5.0	ns
t <sub>PEXP</sub>	Parallel expander delay			0.8		0.8	ns
$t_{LAD}$	Logic array delay			5.0		5.0	ns
t <sub>LAC</sub>	Logic control array delay			5.0		5.0	ns
t <sub>IOE</sub>	Internal output enable delay	(2)		2.0		2.0	ns
t <sub>OD1</sub>	Output buffer and pad delay Slow slew rate = off V <sub>CCIO</sub> = 5.0 V	C1 = 35 pF		1.5		2.0	ns
t <sub>OD2</sub>	Output buffer and pad delay Slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF (7)		2.0		2.5	ns
t <sub>OD3</sub>	Output buffer and pad delay Slow slew rate = on V <sub>CCIO</sub> = 5.0 V or 3.3 V	C1 = 35 pF (2)		5.5		6.0	ns
t <sub>ZX1</sub>	Output buffer enable delay Slow slew rate = off V <sub>CCIO</sub> = 5.0 V	C1 = 35 pF		5.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay Slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF (7)		5.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay Slow slew rate = on V <sub>CCIO</sub> = 5.0 V or 3.3 V	C1 = 35 pF (2)		9.0		9.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		5.0		5.0	ns
$t_{SU}$	Register setup time		2.0		3.0		ns
$t_H$	Register hold time		3.0		3.0		ns
t <sub>FSU</sub>	Register setup time of fast input	(2)	3.0		3.0		ns
$t_{FH}$	Register hold time of fast input	(2)	0.5		0.5		ns
$t_{RD}$	Register delay			2.0		1.0	ns
t <sub>COMB</sub>	Combinatorial delay			2.0		1.0	ns
t <sub>IC</sub>	Array clock delay			5.0		5.0	ns
$t_{EN}$	Register enable time			5.0		5.0	ns
t <sub>GLOB</sub>	Global control delay			1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			3.0		3.0	ns
t <sub>CLR</sub>	Register clear time			3.0		3.0	ns
$t_{PIA}$	PIA delay			1.0		1.0	ns
t <sub>LPA</sub>	Low-power adder	(8)		11.0		11.0	ns

Table 2	23. MAX 7000 & MAX 7000E Ext	ernal Timing Param	<b>eters</b> Note	e (1)			
Symbol	Parameter	Conditions		Speed	Grade		Unit
			MAX 700	0E (-12P)	MAX 70		
			Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t <sub>SU</sub>	Global clock setup time		7.0		10.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		6.0		6.0	ns
t <sub>CH</sub>	Global clock high time		4.0		4.0		ns
t <sub>CL</sub>	Global clock low time		4.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		3.0		4.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		12.0		12.0	ns
t <sub>ACH</sub>	Array clock high time		5.0		5.0		ns
t <sub>ACL</sub>	Array clock low time		5.0		5.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	5.0		5.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			11.0		11.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	90.9		90.9		MHz
t <sub>ACNT</sub>	Minimum array clock period			11.0		11.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	90.9		90.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	125.0		125.0		MHz

Table 2	5. MAX 7000 & MAX 7000E	External Timing I	Paramete	ers /	lote (1)				
Symbol	Parameter	Conditions			Speed	Grade			Unit
			-	15	-1	5T	-2	20	
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>SU</sub>	Global clock setup time		11.0		11.0		12.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		-		5.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		-		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		8.0		8.0		12.0	ns
t <sub>CH</sub>	Global clock high time		5.0		6.0		6.0		ns
t <sub>CL</sub>	Global clock low time		5.0		6.0		6.0		ns
t <sub>ASU</sub>	Array clock setup time		4.0		4.0		5.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		5.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>ACH</sub>	Array clock high time		6.0		6.5		8.0		ns
t <sub>ACL</sub>	Array clock low time		6.0		6.5		8.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	6.0		6.5		8.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			13.0		13.0		16.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	76.9		76.9		62.5		MHz
t <sub>ACNT</sub>	Minimum array clock period			13.0		13.0		16.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	76.9		76.9		62.5		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	100		83.3	_	83.3	_	MHz

Table 29. EPM7064S External Timing Parameters (Part 2 of 2) Note (1)											
Symbol	ymbol Parameter Conditions Speed Grade									Unit	
			-	5	-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		5.4		6.7		7.5		10.0	ns
t <sub>ACH</sub>	Array clock high time		2.5		2.5		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.5		2.5		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			5.7		7.1		8.0		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	175.4		140.8		125.0		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			5.7		7.1		8.0		10.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(4)	175.4		140.8		125.0		100.0		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	250.0		200.0		166.7		125.0		MHz

Table 30. EPM7064S Internal Timing Parameters (Part 1 of 2) Note (1)											
Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	5	-	6	-	7	-1	10	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t <sub>FIN</sub>	Fast input delay			2.2		2.6		1.0		1.0	ns
t <sub>SEXP</sub>	Shared expander delay			3.1		3.8		4.0		5.0	ns
$t_{PEXP}$	Parallel expander delay			0.9		1.1		0.8		0.8	ns
$t_{LAD}$	Logic array delay			2.6		3.2		3.0		5.0	ns
t <sub>LAC</sub>	Logic control array delay			2.5		3.2		3.0		5.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.7		0.8		2.0		2.0	ns
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.2		0.3		2.0		1.5	ns
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		0.7		0.8		2.5		2.0	ns
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.2		5.3		7.0		5.5	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		4.0		4.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		4.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		9.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		4.0		5.0	ns
t <sub>SU</sub>	Register setup time		0.8		1.0		3.0		2.0		ns
t <sub>H</sub>	Register hold time		1.7		2.0		2.0		3.0		ns

Table 3	Table 33. EPM7160S External Timing Parameters (Part 2 of 2) Note (1)										
Symbol	Parameter	Conditions	ns Speed Grade Un						Unit		
			-6 -7 -10 -15								
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>ACNT</sub>	Minimum array clock period			6.7		8.2		10.0		13.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(4)	149.3		122.0		100.0		76.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	166.7		166.7		125.0		100.0		MHz

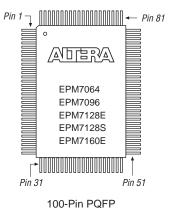
Table 34. EPM7160S Internal Timing Parameters (Part 1 of 2) Note (1)											
Symbol	Parameter	Conditions				Speed	Grade				Unit
			-6		-7		-10		-15		-
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.2		0.3		0.5		2.0	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.2		0.3		0.5		2.0	ns
t <sub>FIN</sub>	Fast input delay			2.6		3.2		1.0		2.0	ns
t <sub>SEXP</sub>	Shared expander delay			3.6		4.3		5.0		8.0	ns
t <sub>PEXP</sub>	Parallel expander delay			1.0		1.3		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.8		3.4		5.0		6.0	ns
t <sub>LAC</sub>	Logic control array delay			2.8		3.4		5.0		6.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.7		0.9		2.0		3.0	ns
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.4		0.5		1.5		4.0	ns
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		0.9		1.0		2.0		5.0	ns
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.4		5.5		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		4.0		5.0		6.0	ns
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		5.5		7.0	ns
t <sub>ZX3</sub>	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		10.0	ns
t <sub>XZ</sub>	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		6.0	ns
t <sub>SU</sub>	Register setup time		1.0		1.2		2.0		4.0		ns
t <sub>H</sub>	Register hold time		1.6		2.0		3.0		4.0		ns
t <sub>FSU</sub>	Register setup time of fast input		1.9		2.2		3.0		2.0		ns
t <sub>FH</sub>	Register hold time of fast input		0.6		0.8		0.5		1.0		ns
$t_{RD}$	Register delay			1.3		1.6		2.0		1.0	ns
t <sub>COMB</sub>	Combinatorial delay			1.0		1.3		2.0		1.0	ns
t <sub>IC</sub>	Array clock delay			2.9		3.5		5.0		6.0	ns
t <sub>EN</sub>	Register enable time			2.8		3.4		5.0		6.0	ns
t <sub>GLOB</sub>	Global control delay			2.0		2.4		1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			2.4		3.0		3.0		4.0	ns

Table 39. MAX 7000 I <sub>CC</sub> Equation Constants									
Device	Α	В	С						
EPM7032	1.87	0.52	0.144						
EPM7064	1.63	0.74	0.144						
EPM7096	1.63	0.74	0.144						
EPM7128E	1.17	0.54	0.096						
EPM7160E	1.17	0.54	0.096						
EPM7192E	1.17	0.54	0.096						
EPM7256E	1.17	0.54	0.096						
EPM7032S	0.93	0.40	0.040						
EPM7064S	0.93	0.40	0.040						
EPM7128S	0.93	0.40	0.040						
EPM7160S	0.93	0.40	0.040						
EPM7192S	0.93	0.40	0.040						
EPM7256S	0.93	0.40	0.040						

This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  values should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figure 19. 100-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



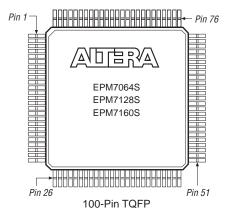
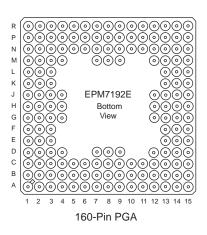
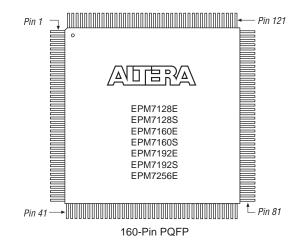


Figure 20. 160-Pin Package Pin-Out Diagram

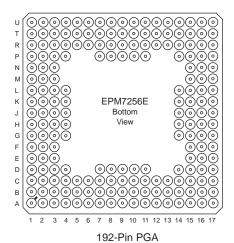
Package outline not drawn to scale.





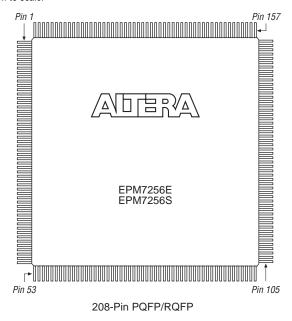
## Figure 21. 192-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



## Figure 22. 208-Pin Package Pin-Out Diagram

Package outline not drawn to scale.





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